

Figure 1. Process flow and schematic of Hybrid-ASD.

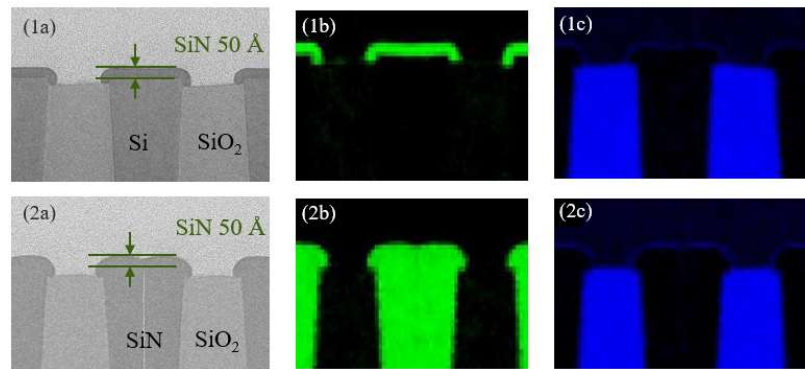


Figure 2. Stripe-patterned samples of (1) a-Si/SiO<sub>2</sub> and (2) SiN/SiO<sub>2</sub> treated by COR and SiN-ALD: (a) TEM image, EELS mapping of (b) nitrogen and (c) oxygen. Source: TEL

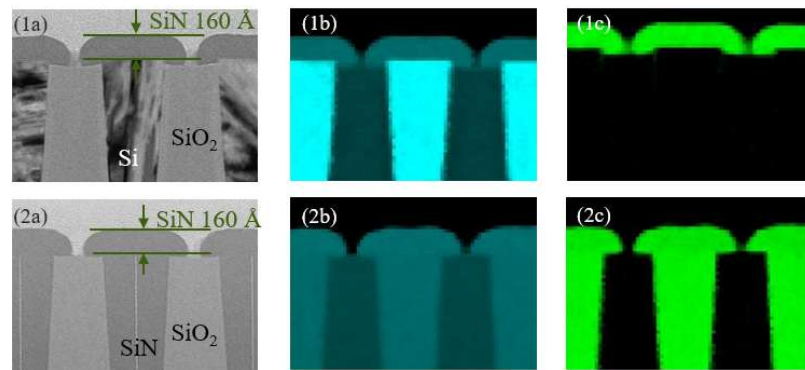


Figure 3. Stripe-patterned samples of (1) a-Si/SiO<sub>2</sub> and (2) SiN/SiO<sub>2</sub> treated by Hybrid-ASD: (a) TEM image, EELS mapping of (b) silicon and (c) nitrogen. Source: TEL